

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- BLACK BORDERS**
- IMAGE CUT OFF AT TOP, BOTTOM OR SIDES**
- FADED TEXT OR DRAWING**
- BLURRED OR ILLEGIBLE TEXT OR DRAWING**
- SKEWED/SLANTED IMAGES**
- COLOR OR BLACK AND WHITE PHOTOGRAPHS**
- GRAY SCALE DOCUMENTS**
- LINES OR MARKS ON ORIGINAL DOCUMENT**
- REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY**
- OTHER: _____**

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)

» See

[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)

RELEASE 15

Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)**Quick Links****Welcome to IEEE Xplore®**

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

Enterprise File Cabinet

- Access the IEEE Enterprise File Cabinet

Print Format[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[Abstract] [PDF Full-Text (696 KB)] IEEE CNF

5 Color error-diffusion halftoning

Dantera-Venkata, N.; Evans, B.L.; Monga, V.;
Signal Processing Magazine, IEEE , Volume: 20 , Issue: 4 , July 2003
Pages:51 - 58

[Abstract] [PDF Full-Text (2843 KB)] IEEE JNL

6 On spatial quantization of color images

Puzicha, J.; Held, M.; Ketterer, J.; Buhmann, J.M.; Fellner, D.W.;
Image Processing, IEEE Transactions on , Volume: 9 , Issue: 4 , April 2000
Pages:666 - 682

[Abstract] [PDF Full-Text (1548 KB)] IEEE JNL

7 Model-based digital halftoning

Pappas, T.N.; Allebach, J.P.; Neuhoff, D.L.;
Signal Processing Magazine, IEEE , Volume: 20 , Issue: 4 , July 2003
Pages:14 - 27

[Abstract] [PDF Full-Text (2122 KB)] IEEE JNL

8 A new moire smoothing method for color inverse halftoning

Youngmee Han; Jongmin Kim; Minhwan Kim;
Image Processing. 2002. Proceedings. 2002 International Conference on , Vol 1 , 22-25 Sept. 2002
Pages:I-820 - I-823 vol.1

[Abstract] [PDF Full-Text (353 KB)] IEEE CNF

9 Fast and accurate binary halftone image resolution increasing by decision-tree learning

Hae Yong Kim;
Image Processing, 2001. Proceedings. 2001 International Conference on , Vol 2 , 7-10 Oct. 2001
Pages:1093 - 1096 vol.2

[Abstract] [PDF Full-Text (512 KB)] IEEE CNF

10 QR-RLS algorithm for error diffusion of color images

Bozkurt, G.; Yardimci, Y.; Ankan, O.; Cetin, E.;
Image Processing, 1998. ICIP 98. Proceedings. 1998 International Conference on , Volume: 2 , 4-7 Oct. 1998
Pages:49 - 53 vol.2

[Abstract] [PDF Full-Text (708 KB)] IEEE CNF

11 A wide-viewing-angle 10-inch-diagonal full-colour active-matrix LC using a halftone-grayscale method

Sunata, T.; Inada, T.; Nakagawa, T.; Matsushita, Y.; Ugai, Y.; Aoki, S.;
Display Research Conference, 1991., Conference Record of the 1991

International , 15-17 Oct. 1991
Pages:255 - 257

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) [IEEE CNF](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) |
[New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)

» Se

Welcome to IEEE Xplore

- [Home](#)
- [What Can I Access?](#)
- [Log-out](#)

Tables of Contents

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)
- [CrossRef](#)

Member Services

- [Join IEEE](#)
- [Establish IEEE Web Account](#)
- [Access the IEEE Member Digital Library](#)

IEEE Standards

- [Access the IEEE Enterprise File Cabinet](#)

Print Format[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

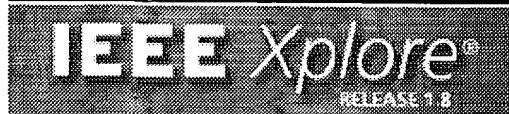
[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)



II
1
1

» Se

[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)



Welcome
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Xplore®

- Access the IEEE Enterprise File Cabinet

[Print Format](#)

Your search matched **9 of 1085387** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

halfton* and edge and pixel

Search

Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Retrieval of gray images from digital halftones

Fan, Z.;

Circuits and Systems, 1992. ISCAS '92. Proceedings., 1992 IEEE International Symposium on , Volume: 5 , 3-6 May 1992

Pages:2477 - 2480 vol.5

[\[Abstract\]](#) [\[PDF Full-Text \(420 KB\)\]](#) **IEEE CNF**

2 Using vector quantization for image processing

Cosman, P.C.; Oehler, K.L.; Riskin, E.A.; Gray, R.M.;

Proceedings of the IEEE , Volume: 81 , Issue: 9 , Sept. 1993

Pages:1326 - 1341

[\[Abstract\]](#) [\[PDF Full-Text \(1892 KB\)\]](#) **IEEE JNL**

3 Digital image halftoning by noise thresholding

Makur, A.; Raghubeer, M.R.;

Acoustics, Speech, and Signal Processing, 1995. ICASSP-95., 1995 International Conference on , Volume: 4 , 9-12 May 1995

Pages:2535 - 2538 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(492 KB\)\]](#) **IEEE CNF**

4 Adaptive threshold modulation for error diffusion halftoning

Damera-Venkata, N.; Evans, B.L.;

Image Processing, IEEE Transactions on , Volume: 10 , Issue: 1 , Jan. 2001

Pages:104 - 116

[\[Abstract\]](#) [\[PDF Full-Text \(1740 KB\)\]](#) **IEEE JNL**

5 Edge enhancement in clustered-dot dithering

Vander Kam, R.A.; Ping Wah Wong;

Image Processing, 1996. Proceedings., International Conference on , Volume:

1 , 16-19 Sept. 1996

Pages:857 - 860 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(424 KB\)\]](#) [IEEE CNF](#)

6 Tone-dependent error diffusion

Pingshan Li; Allebach, J.P.;

Image Processing, IEEE Transactions on , Volume: 13 , Issue: 2 , Feb. 2004

Pages:201 - 215

[\[Abstract\]](#) [\[PDF Full-Text \(1344 KB\)\]](#) [IEEE JNL](#)

7 Modeling and quality assessment of halftoning by error diffusion

Kite, T.D.; Evans, B.L.; Bovik, A.C.;

Image Processing, IEEE Transactions on , Volume: 9 , Issue: 5 , May 2000

Pages:909 - 922

[\[Abstract\]](#) [\[PDF Full-Text \(2076 KB\)\]](#) [IEEE JNL](#)

8 Inverse halftoning using binary permutation filters

Yeong-Taeg Kim; Arce, G.R.; Grabowski, N.;

Image Processing, IEEE Transactions on , Volume: 4 , Issue: 9 , Sept. 1995

Pages:1296 - 1311

[\[Abstract\]](#) [\[PDF Full-Text \(3140 KB\)\]](#) [IEEE JNL](#)

9 Automatic registration of color separation films

Medioni, G.; Wilson, M.; Huertas, A.;

Robotics and Automation, 1990. Proceedings., 1990 IEEE International Conference , 13-18 May 1990

Pages:1495 - 1502 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(696 KB\)\]](#) [IEEE CNF](#)
